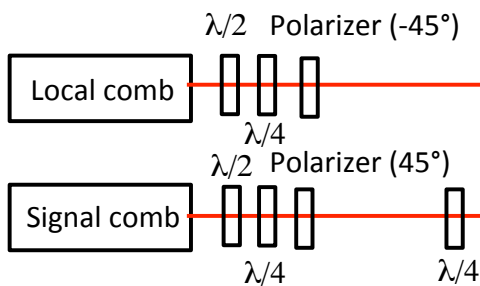
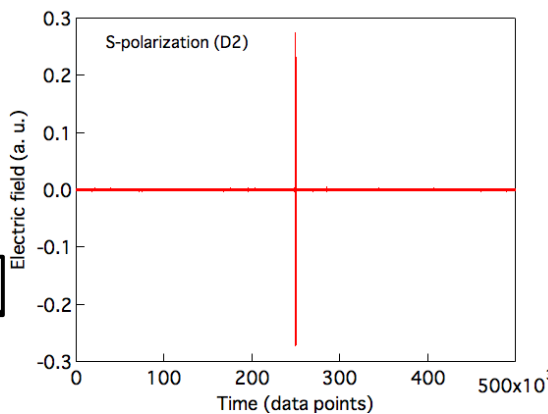


# QWP測定

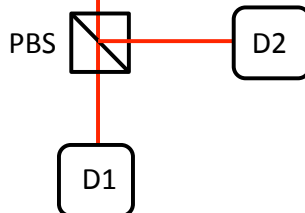
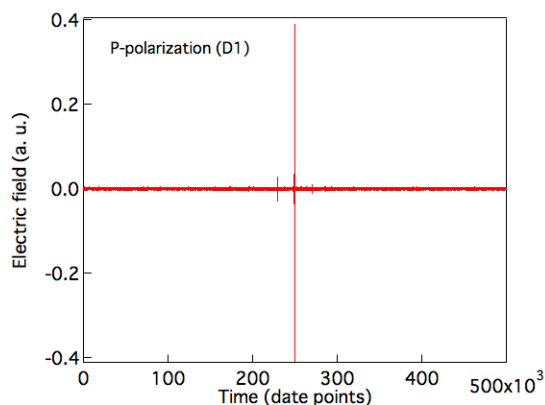
実験装置:



測定前:



測定前:

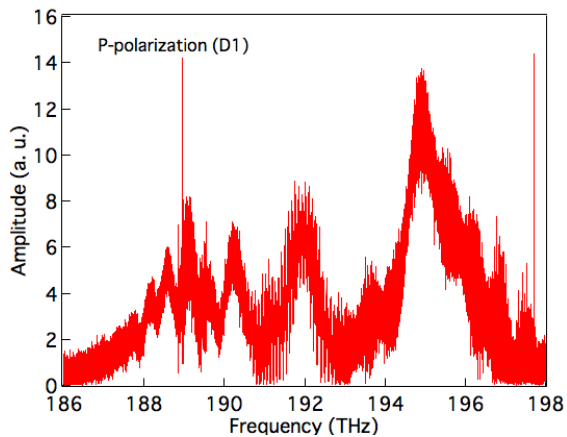


$f_{\text{rep(sig)}}: 48350213.0043859\text{Hz}$

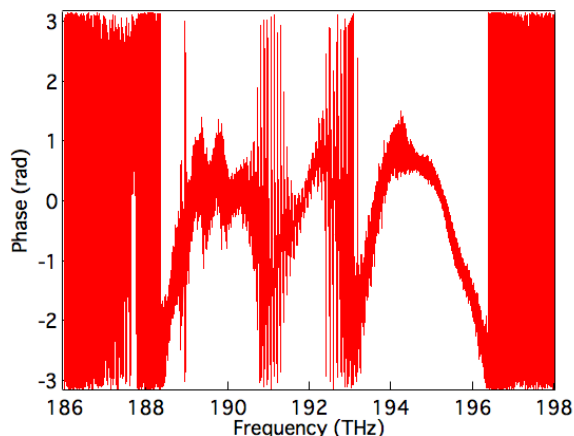
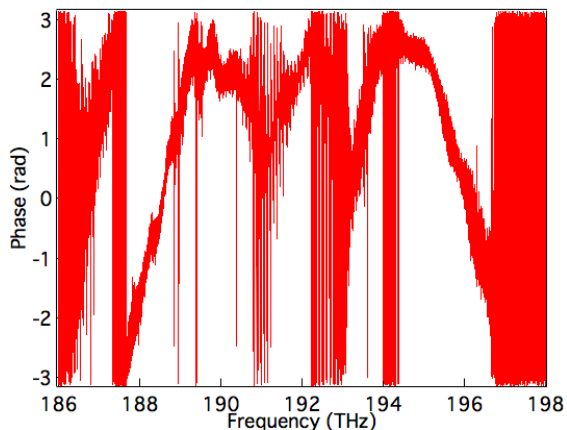
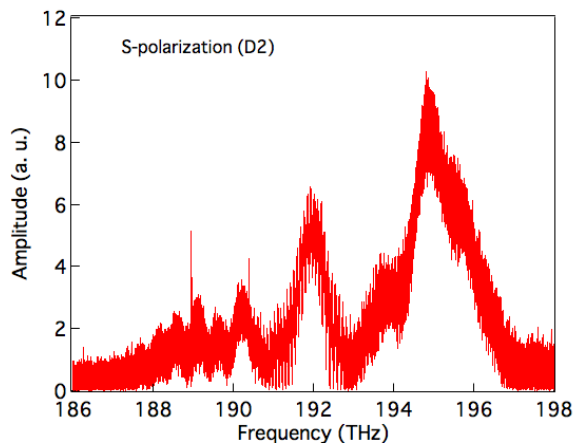
$f_{\text{rep(LO)}}: 48350179.9817047\text{Hz}$

$\Delta f: 33.0239362757913\text{Hz}$

P偏光:

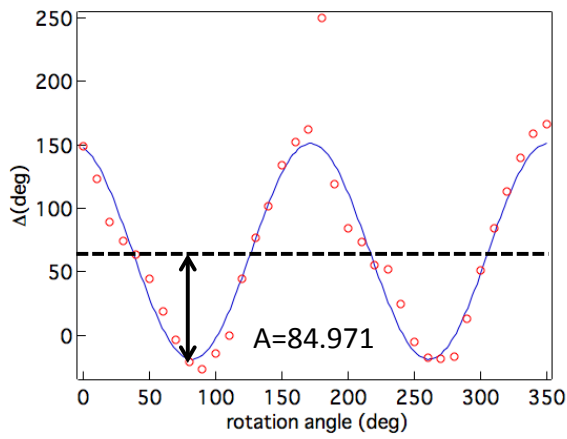
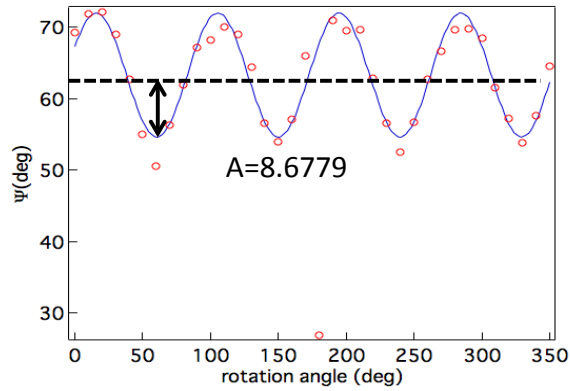


S偏光:

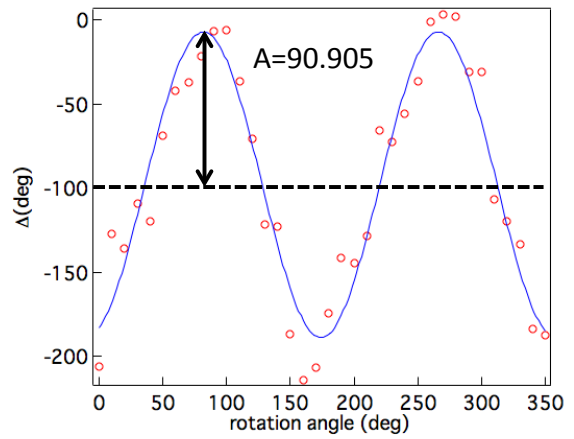
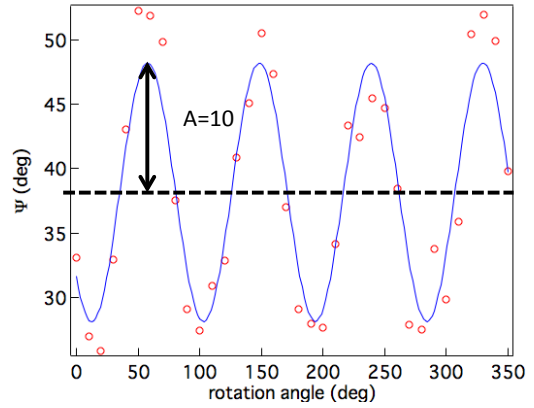


QWP測定結果:

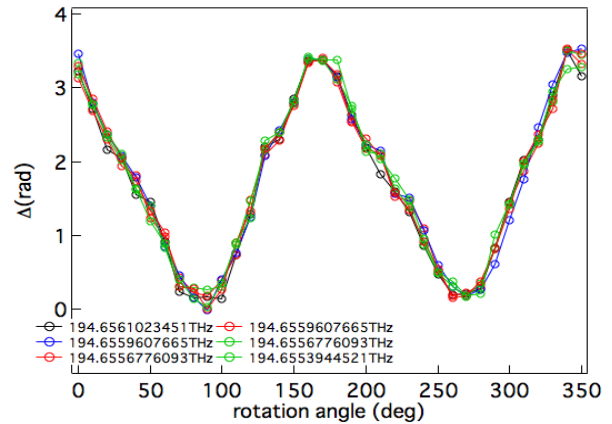
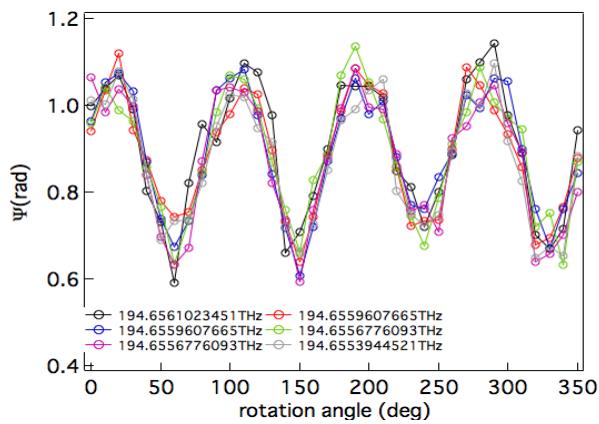
1回目:



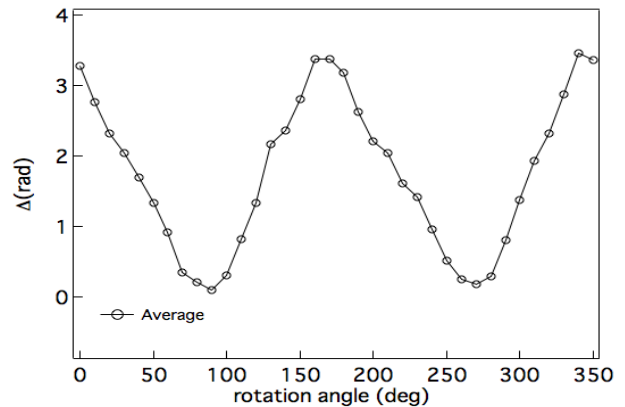
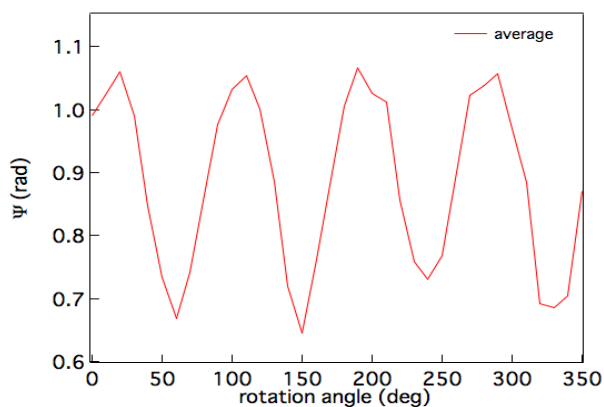
2回目:



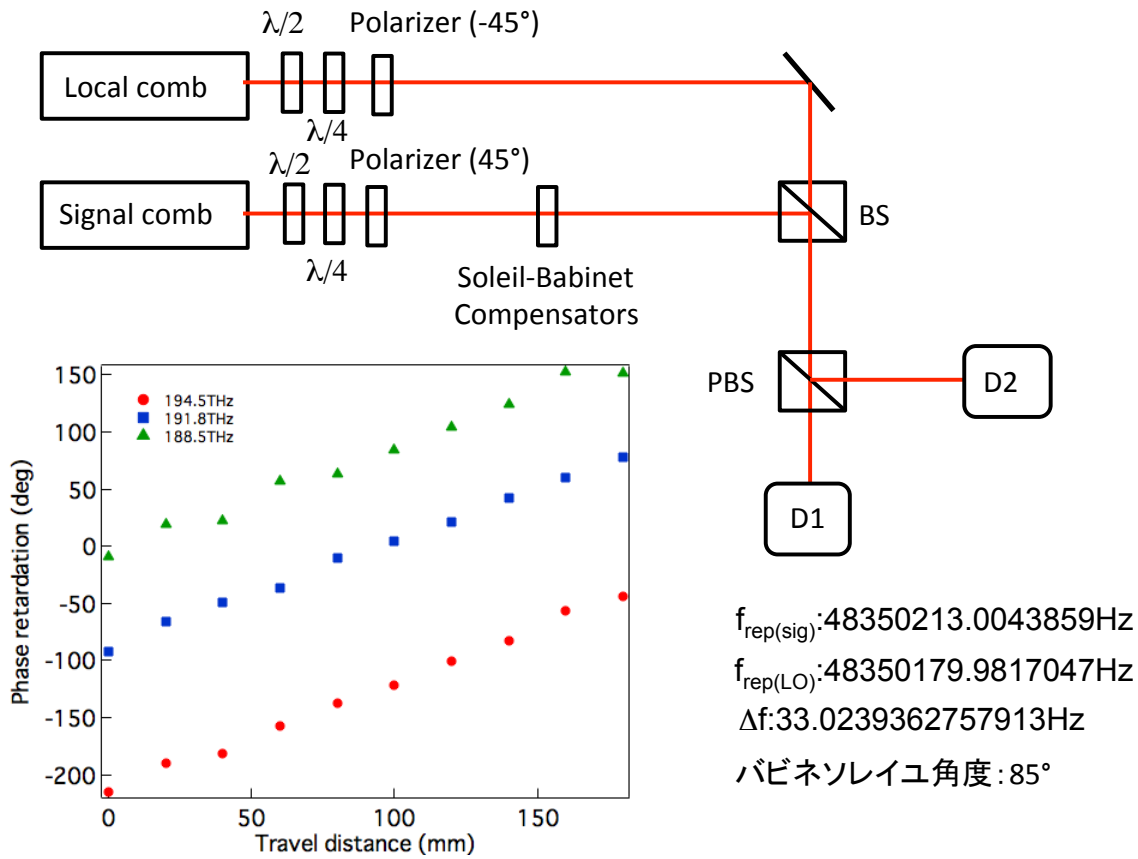
194THz付近:



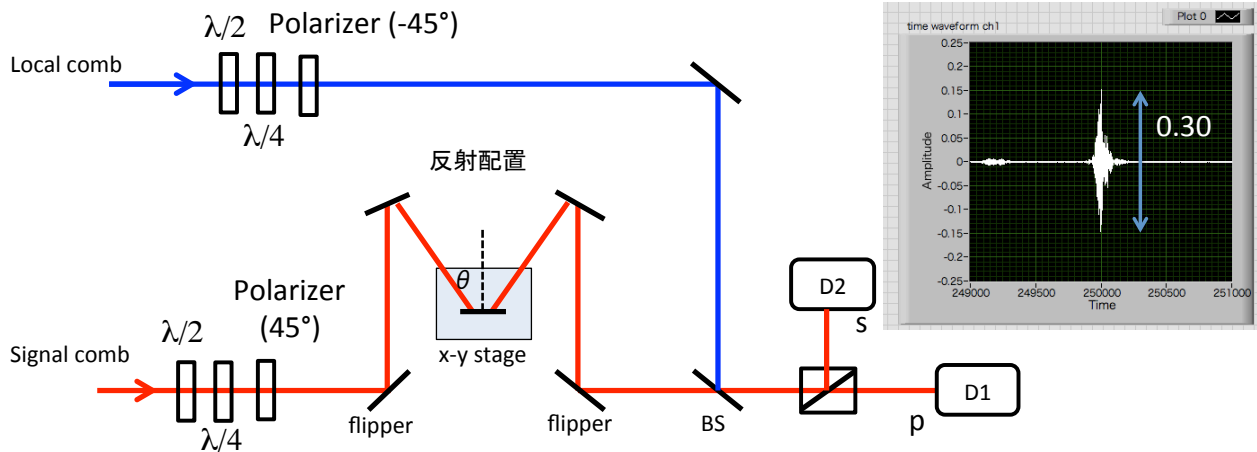
平均:



# Soleil-Babinet Compensators



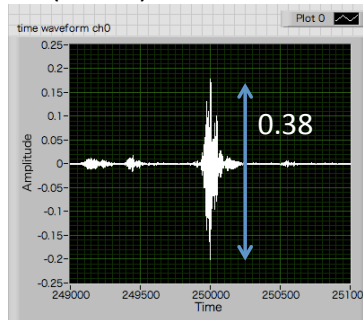
# SiO<sub>2</sub>測定



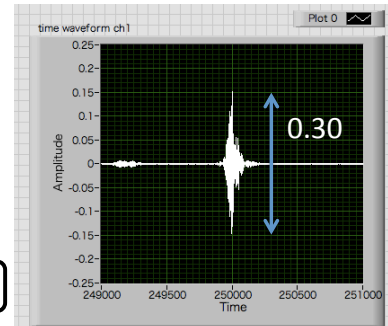
## Experimental condition

Sample	SiO <sub>2</sub> layer on Si substrate
Incident angle [deg.]	$\cong 55\sim 60$
averaging number of interferogram	100

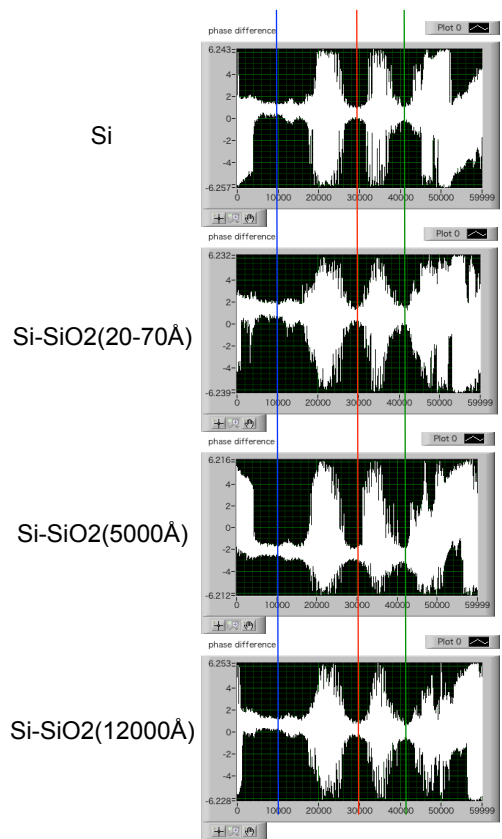
## D1(P成分)



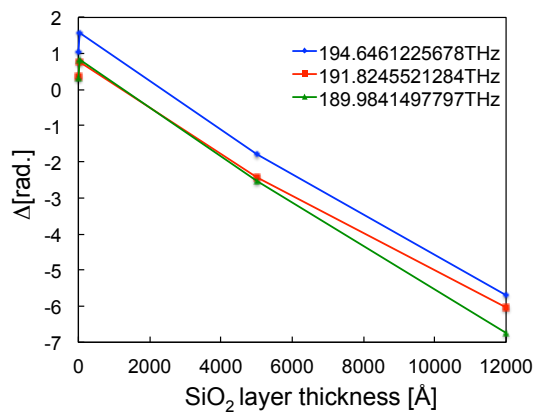
## D2(S成分)



### S-P phase difference



### Experimental result



### Experimental result2(再実験)

